Unconfirmed Meeting Minutes: IEEE 802.3 Isolation Ad Hoc

22 May 2018 Pittsburgh, PA USA

Prepared by Jon Lewis

Meeting called to order 22 May 2018 at 7:00 AM Eastern Time (US).

Chaired by Jon Lewis, Dell EMC

The Chair read asked if anyone was not familiar with the patent policy and participation slide, none responded. The Chair then read the participation slide, reviewed the ad hoc information, webpage and reflector information.

Presentations:

Isolation Ad-Hoc: Moving Forward –Jon Lewis, Dell EMC

Discussion on the proposed isolation text including the need to reword the proposed text removing references to specific tests. Consideration should also include multi-port PSEs or Bridges from a port-to-port isolation perspective.

For Network safety it was agreed that this was in scope and should be handled in a similar manner as isolation. Specific text edits were discussed.

Laser Safety was skipped due to a lack of experts in the room. Steve Carlson volunteered to work with the experts to confirm the text in clause 122 was up-to-date.

NOTE: During minutes review it was determined that clause 122 is up-to-date.

Environmental Safety was briefly discussed but due to time constraints will need to be discussed further prior to proposed text can be completed.

The Chair announced that the next meeting of the ad hoc would be sent to the reflector.

The ad hoc was adjourned at 7:59 AM Eastern Time (US).

Attendance:

IEEE 802.3 Isolation Ad Hoc				5/22/18
Last Name	First Name	Employer	Affiliation	Tuesday
Amason	Dale	NXP	NXP	Χ
Bains	Amrik	Cisco	Cisco	X
Brownlee	Phillip	TDK	TDK	X
Carlson	Steve	High Speed Design	Robert Bosch	X
Goldberg	Jonathan	IEEE-SA	IEEE-SA	X
Graber	Steffen	Pepperl+Fuchs	Pepperl+Fuchs	X
Horrmeyer	Bernd	Phoenix Contact	Phoenix Contact	X
Huszak	Gergely	Kone	Kone	X
Kattainen	Ari	Kone	Kone	X
Lewis	Jon	Dell EMC	Dell EMC	X
Lin	Bin	TE Connectivity	TE Connectivity	X
Peker	Arkadiy	Microsemi	Microsemi	X
Renteria	Victor	Bel Fuse Inc.	Bel Fuse Inc.	Χ
Thompson	Geoff	GraCaSI SA.	Independent	Х
Withey	James	Fluke	Fluke	X